100V, 467A, 1.0mΩ N-channel Power SGT MOSFET

JMSH1001MTL

Features

- $\bullet \quad \text{Excellent $R_{\text{DS(ON)}}$ and Low Gate Charge}$
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant

Applications

- Load Switch
- PWM Application
- Power Management

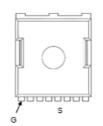
Product Summary

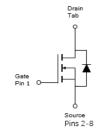
Parameters	Value	Unit
V_{DSS}	100	V
$V_{GS(th)_Typ}$	2.9	V
$I_D(@V_{GS}=10V)$	467	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	1.0	mΩ











PowerJE®10x12

Pin Assignment

Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSH1001MTL-13	SH1001M	1	Tape&Reel	PowerJE®10x12	2000	10000

Absolute Maximum Ratings (@ $T_C = 25$ °C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		100	V
V_{GS}	Gate-to-Source Voltage		±20	V
I_	Continuous Drain Current	$T_C = 25$ °C	467	А
I _D		$T_C = 100$ °C	295	
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α
E _{AS}	Single Pulsed Avalanche Energy (2)		1987	mJ
P _D	Power Dissipation	$T_C = 25^{\circ}C$	500	W
		$T_C = 100$ °C	200	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \
T_{J}, T_{STG}	Junction & Storage Temperature Range		-55 to 150	°C

Thermal Characteristics

Symbol Parameter		Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	33	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.25	C/ VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

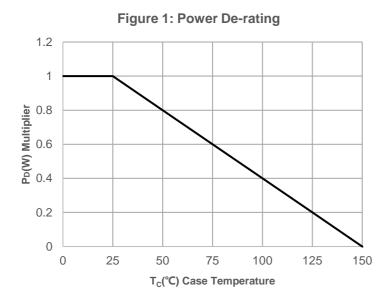
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0	2.9	3.8	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_D = 20A$	-	1.0	1.3	mΩ
Dynami	ic Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	3.8	1	Ω
C _{iss}	Input Capacitance	., ., ., ., .,	9543	13360	18036	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V,$ f = 1MHz	3652	5113	6902	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	87	122	164	pF
Qg	Total Gate Charge		155	217	293	nC
Q _{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_D = 20A$	47	65	88	nC
Q_{gd}	Gate Drain("Miller") Charge	V DS = 30 V, 10 = 20/1	41	57	77	nC
<u> </u>						
	ng Characteristics	1		Π	T .	
t _{d(on)}	Turn-On DelayTime		-	41	-	ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 50V$	-	69	-	ns
$t_{d(off)}$	Turn-Off DelayTime	$I_D = 20A, R_{GEN} = 3\Omega$	-	157	-	ns
t _f	Turn-Off Fall Time		-	92	-	ns
Body D	iode Characteristics			1	T	
I _S	Maximum Continuous Body Diode Forward Current		-	-	467	Α
I_{SM}	Maximum Pulsed Body Diode Forward Curre	ent	-	-	1866	Α
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/us	93	130	176	ns
Qrr	Body Diode Reverse Recovery Charge	7 1F - 2017, UI/UI = 1001/US	-	374	-	nC

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- $2.\;E_{AS}\;condition:\;Starting\;T_J=25C,\;V_{DD}=50V,\;V_{GS}=10V,\;R_G=25ohm,\;L=3mH,\;I_{AS}=36.4A,\;V_{DD}=0V\;during\;time\;in\;avalanche.$
- 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.
- 4. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 0.5%.



Typical Performance Characteristics



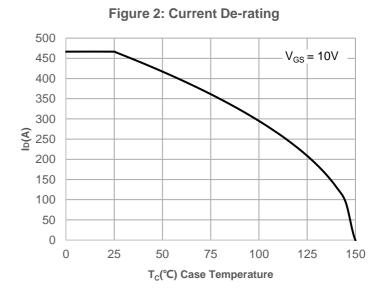
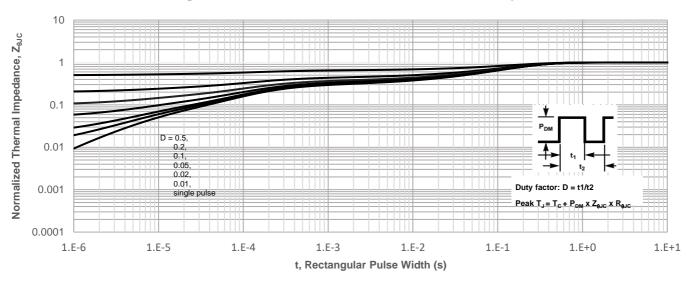
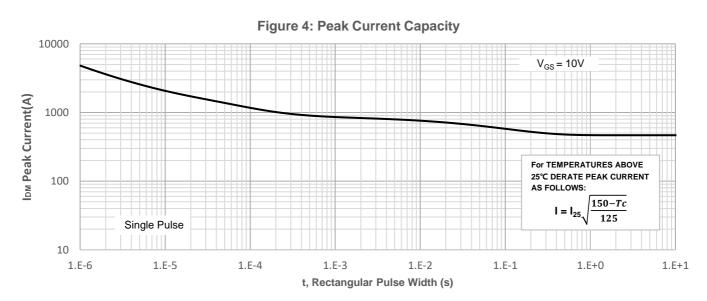


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

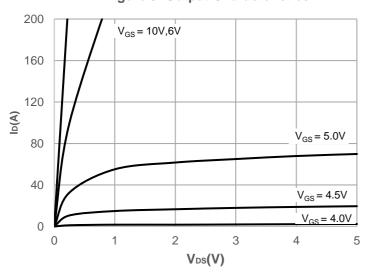


Figure 6: Typical Transfer Characteristics

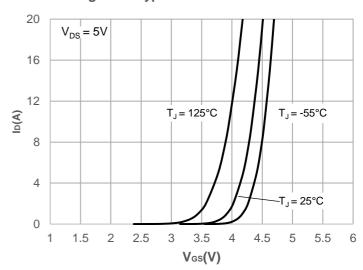


Figure 7: On-resistance vs. Drain Current

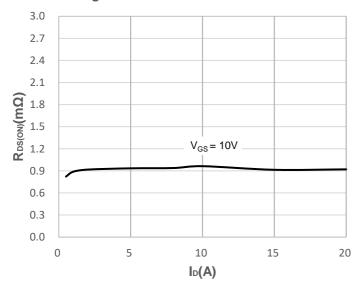


Figure 8: Body Diode Characteristics

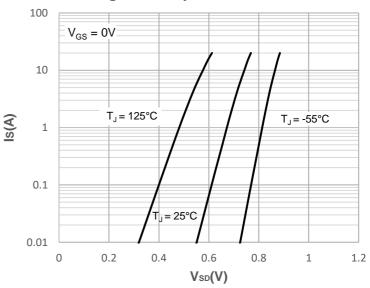


Figure 9: Gate Charge Characteristics

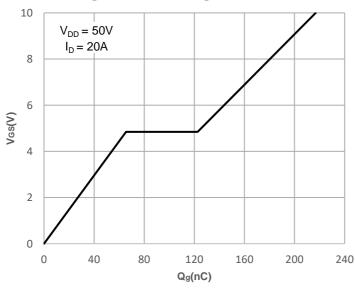
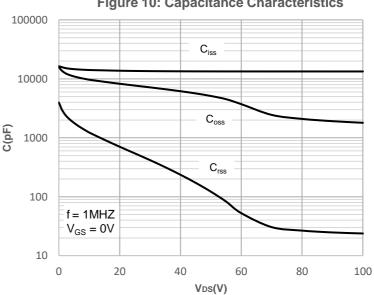


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

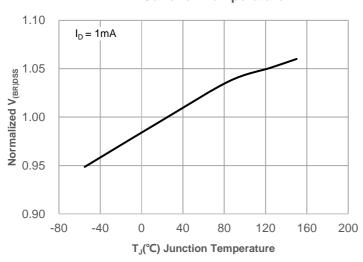


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

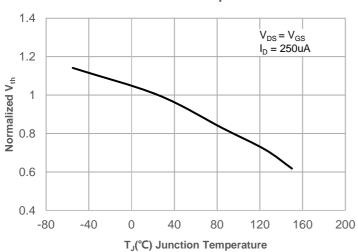


Figure 15: Maximum Safe Operating Area

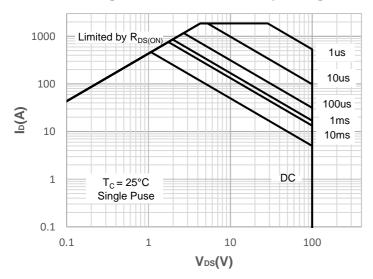
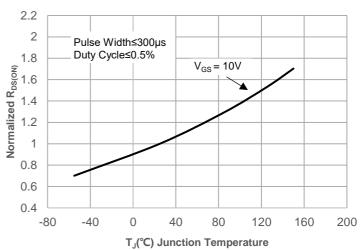
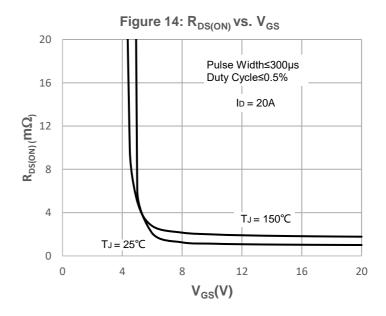


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

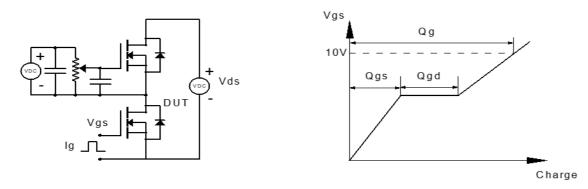


Figure 1: Gate Charge Test Circuit & Waveform

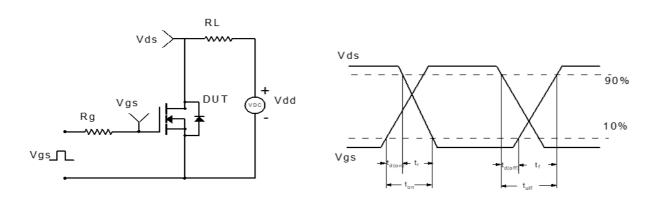


Figure 2: Resistive Switching Test Circuit & Waveform

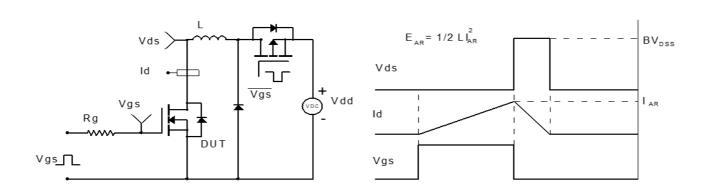


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

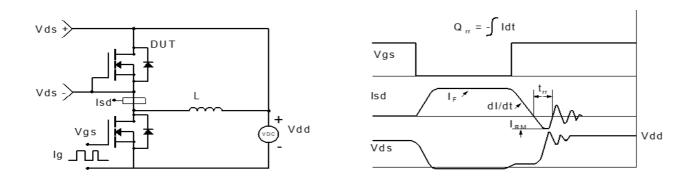
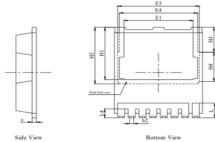


Figure 4: Diode Recovery Test Circuit & Waveform



Package Mechanical Data(PowerJE®10x12)



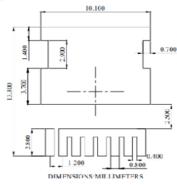






DIM.	MILLIMETER				
DIIVI.	MIN	MAX			
Α	2.20	2.30	2.50		
b	0.70	0.80 0.90			
bl	9.70	9.80	9.90		
b2	0.42	0.46	0.50		
С	0.40	0.50	0.65		
D	10.28	10.38	10.58		
D2		3.30			
E	9.70	9.90	10.10		
E1		7.80			
E4	8.80				
E5	9.20				
e		1.20(BSC)			
Н	11.48	11.68	11.88		
HI	6.55	6.75	6.85		
H2		7.30			
H3	3.20				
H4	3.80				
K1	4.18				
L	1.70 1.90 2.10				
L1	0.70				
L2	0.60				
L4	1.00 1.15 1.30				

Recommended Soldering Footprint



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